



Precision Low-Input Current Operational Amplifier (Internally Compensated)

OP12

1.0 SCOPE

This specification documents the detail requirements for space qualified product manufactured on Analog Devices, Inc.'s QML certified line per MIL-PRF-38535 Level V except as modified herein. The manufacturing flow described in the STANDARD SPACE LEVEL PRODUCTS PROGRAM brochure is to be considered a part of this specification. <http://www.analog.com/aerospace> This data sheet specifically details the space grade version of this product. A more detailed operational description and a complete data sheet for commercial product grades can be found at www.analog.com/OP12

2.0 Part Number. The complete part number(s) of this specification follow:

<u>Part Number</u>	<u>Description</u>
OP12-903J	Precision Low-Input Current Operational Amplifier

2.1 Case Outline.

<u>Letter</u>	<u>Descriptive designator</u>	<u>Case Outline (Lead Finish per MIL-PRF-38535)</u>
J	MACY1-X8	8-Lead metal can (TO)

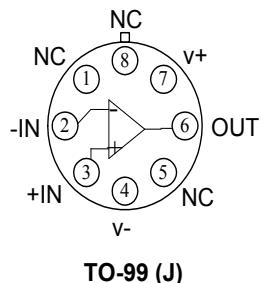


Figure 1 - Terminal connections.

ASD0011410

Rev. F

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One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106,
U.S.A.

Tel: 781.329.4700

www.analog.com

Fax: 781.326.8703

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3.0 Absolute Maximum Ratings. ($T_A = 25^\circ\text{C}$, unless otherwise noted)

Supply Voltage	$\pm 20\text{V}$
Power Dissipation	500mW
Differential Input Current (Note 1).....	$\pm 10\text{mA}$
Input Voltage (Note 2).....	$\pm 15\text{V}$
Output Short-Circuit Duration	Indefinite
Operating Temperature Range	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering, 60 sec.)	+300°C
Dice Junction Temperature (T_J)	-65°C to +150°C
Thermal resistance, junction to case (Θ_{JC})	see MIL-STD-1835
Thermal resistance, junction to ambient (Θ_{JA})		
8-lead metal can (TO).....	150°C/W
8-lead cerdip	119°C/W

NOTES:

1. The inputs are shunted with back-to-back diodes for over voltage protection. Therefore, excessive current will flow if a differential input voltage in excess of 1V is applied between the inputs without some limiting resistance.
2. For supply voltages less than $\pm 15\text{V}$, the absolute maximum input voltage is equal to the supply voltages.

4.0 Electrical Table:

Table I

Parameter See notes at end of table	Symbol	Conditions $V_S = \pm 15\text{V}$, $R_S = 50\Omega$ Unless otherwise specified	Sub-group	Limit Min	Limit Max	Units
Input Offset Voltage	V_{OS}		1		0.15	mV
			2, 3		0.35	
Input Offset Current	I_{OS}		1		0.20	nA
			2, 3		0.40	
Input Bias Current	I_B		1		± 2.0	
			2, 3		± 3.0	
Input Voltage Range 1/	I_{VR}		1, 2, 3	± 13		V
Common-Mode Rejection	CMR	$V_{CM} = \pm 13\text{V}$	1	104		dB
			2, 3	100		
Power Supply Rejection	PSRR	$V_S = \pm 5\text{V}, \pm 15\text{V}$	1		7	$\mu\text{V/V}$
			2, 3		10	
Output Voltage Swing	V_O	$R_L = 10\text{k}\Omega$	4, 5, 6	± 13		V
		$R_L = 5\text{k}\Omega$	4, 5, 6	± 10		
Large-Signal Voltage Gain	A_{VO}	$V_O = \pm 10\text{V}$	$R_L = 10\text{k}\Omega$	4	80	V/mV
			$R_L = 2\text{k}\Omega$	4	50	
			$R_L = 5\text{k}\Omega$	5, 6	40	
Supply Current	I_{SY}	No Load	$V_S = \pm 5\text{V}$	1		mA
			$V_S = \pm 15\text{V}$	2, 3		

1/ IVR is defined as the VCM range used for the CMR test.

4.1 Electrical Test Requirements:

Table II	
Test Requirements	Subgroups (in accordance with MIL-PRF-38535, Table III)
Interim Electrical Parameters	1
Final Electrical Parameters	1, 2, 3, 4, 5, 6 <u>1/ 2/</u>
Group A Test Requirements	1, 2, 3, 4, 5, 6
Group C end-point electrical parameters	1 <u>2/</u>
Group D end-point electrical parameters	1
Group E end-point electrical parameters	1

1/ PDA applies to Subgroup 1. Delta's excluded from PDA.

2/ See Table III for delta parameters. See table I for conditions.

4.2 Table III. Burn-in test delta limits.

Table III				
TEST TITLE	BURN-IN LIMIT	LIFETEST LIMIT	DELTA LIMIT	UNITS
VOS	± 0.15	± 0.225	0.075	mV
$\pm IB$	± 2.0	± 2.5	0.5	nA

5.0 Life Test/Burn-In Circuit:

- 5.1 HTRB is not applicable for this drawing.
- 5.2 Burn-in is per MIL-STD-883 Method 1015 test condition A, B, or C.
- 5.3 Steady state life test is per MIL-STD-883 Method 1005.

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Rev	Description of Change	Date
A	Initiate	Feb. 29, 2000
B	Add flatpack. Add radiation part number. Exclude Delta's from PDA. Delete reference to unused subgroups in table II. Update Table III.	Aug. 21, 2001
C	Update web address.	Feb. 14, 2002
D	Change Table I AC parameters from subgroups 1, 2, 3 to subgroups 9, 10, 11. (SINAD, THD, PS, $\Sigma 2^{\text{nd}}$, and $\Sigma 3^{\text{nd}}$).	Jan. 9, 2003
E	Delete burn-in circuit	Aug. 5, 2003
F	Update header/footer and add to 1.0 scope description.	Feb. 15, 2008